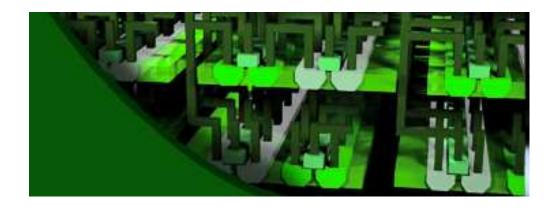
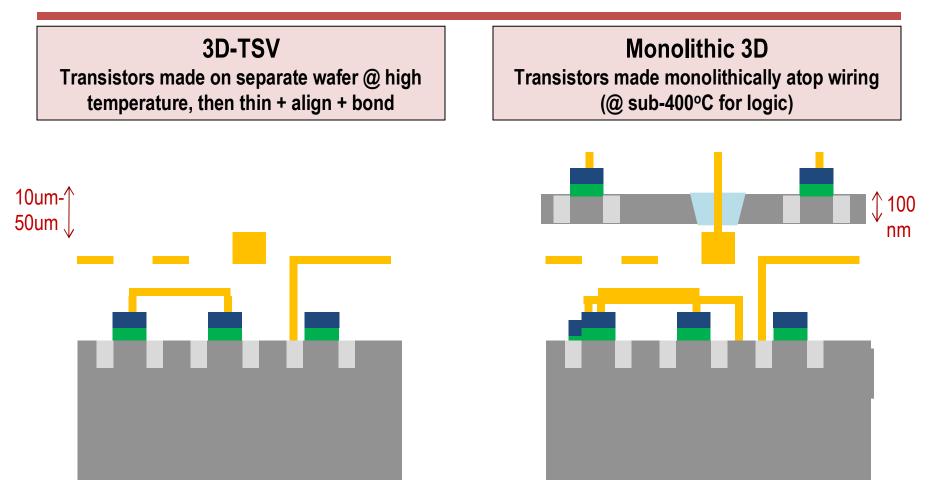
# The Short, Medium and Long-Term Path to the 3D Ecosystem Panel Discussion at EDPS



### A Monolithic 3D-IC Perspective

Deepak C. Sekar Rambus Inc.

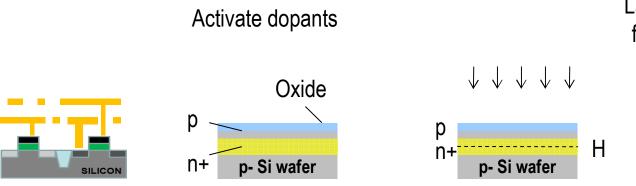
## **Two Types of 3D Technology**



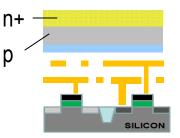
TSV pitch > 1*um*\*

TSV pitch ~ 50-100*nm* 

## A Process Flow for Monolithic 3D: Recessed Channel Transistors with Activation before Layer Transfer

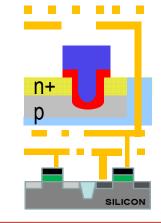


Layer transfer un-patterned film. No alignment issues.



Well-aligned sub-400C RCATs Si thickness < 100nm Min. feature size TSVs since low Si thickness, no misalignment issues

n+ p siLiCON



• Steps atop Cu/low k < 400°C

• RCATs used in production
DRAM since the 90nm node
→ Adoption easier

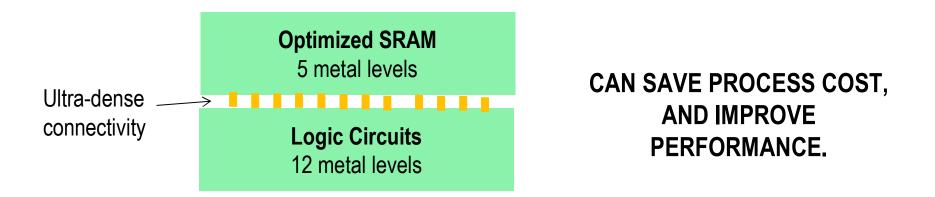
[D. C. Sekar, Z.Or-Bach, "Monolithic 3D-ICs with Single Crystal Silicon Layers", Proc. IEEE 3DIC Conference 2011 (Invited)]

## **SRAM-Logic Stacking**

• SRAM requirements different from logic today.

Different number of metal levels, V<sub>t</sub>, L<sub>eff</sub>...

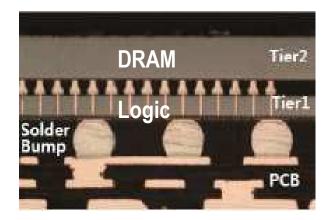
 Ultra-dense vertical connectivity needed, esp. for small size SRAMs within a logic core → good fit for Monolithic 3D



#### EDA need: Tools to partition designs and stack the SRAM

## Logic-Logic Stacking with High TSV Density

### Today "Pseudo-3D" EDA Tools



- Modify existing 2D tools slightly
- TSVs in whitespace or modify existing layout slightly for TSVs to stacked layer
- OK for today's 5um TSVs (low density)

### Needed for Monolithic 3D "Native-3D" EDA Tools

•3D routing, placement, floorplanning tools that work <u>for TSVs close to min.</u> <u>feature size</u>

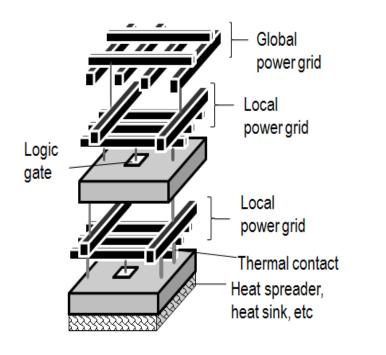
•Support for both block-level and gate-level partitioning

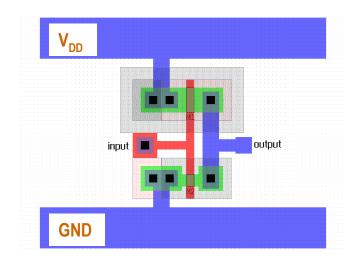


Most logic gates have V<sub>DD</sub> and GND contacts

Low (thermal) resistance power grids  $\rightarrow$  low temp. drop between heat sink and stacked logic gate

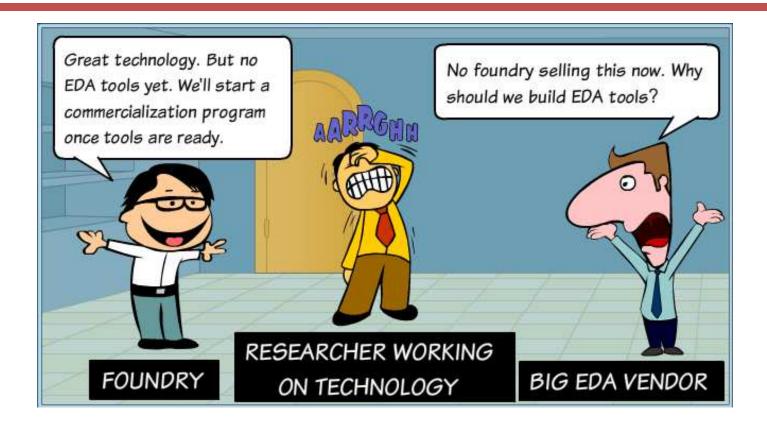
• Promising simulation results





EDA need: Integrate power distribution design with (thermal-aware) place-and-route for monolithic 3D

## How will monolithic 3D technology tackle this familiar problem?



Suggestion to the EDA community:

EDA tools for logic-logic stacking starting to be developed for um-scale TSVs.

Make sure your algorithms are scalable to nm-scale TSVs... they may happen sooner than you think!